Abstracts

Reliability of Super Low Noise HEMTs

K. Hayashi, T. Sonoda, T. Yamaguchi, K. Nagahamar, M. Yamanouchi, S. Takamiya and S. Mitsui. "Reliability of Super Low Noise HEMTs." 1987 MTT-S International Microwave Symposium Digest 87.2 (1987 Vol. II [MWSYM]): 1023-1026.

The first report on a comprehensive study of the reliability of super low noise HEMTs with a typical noise figure of 1.2 dB at 12GHz is presented. No failure was observed in both DC running and high temperature storage tests during 2000 hours. These successful results were achieved by a newly developed low temperature ohmic sintering technology and a novel Ni/Al gate.

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